

Computer Science 246

Advanced Computer Architecture

Spring 2008

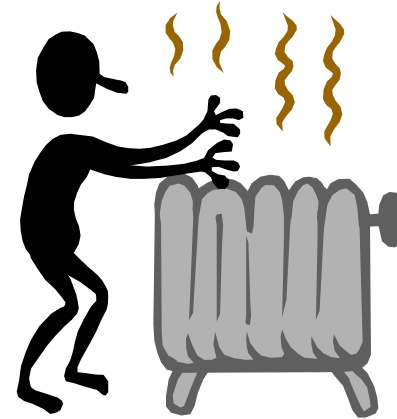
Harvard University

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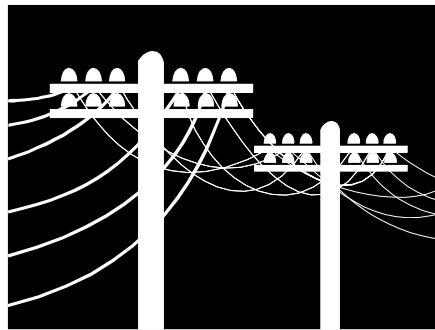
Why worry about power dissipation?

Battery
life



Thermal issues: affect
cooling, packaging,
reliability, timing

Environment



Power-Aware Needed across all computing platforms

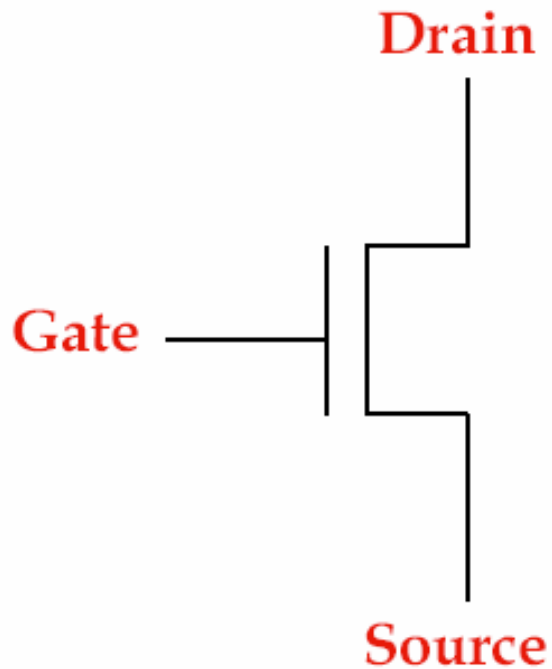
- **Mobile/portable (cell phones, laptops, PDA)**
 - Battery life is critical
- **Desktops/Set-Top (PCs and game machines)**
 - Packaging cost is critical
- **Servers (Mainframes and compute-farms)**
 - Packaging limits
 - Volumetric (performance density)

Modeling + Design

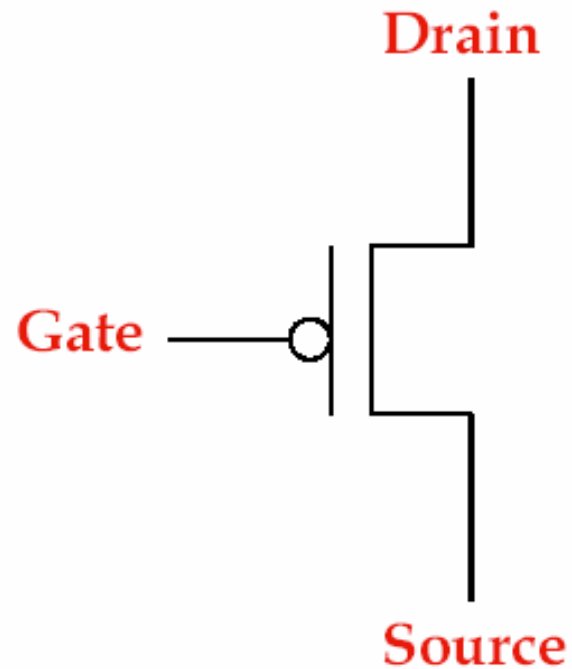
- **First Component (Modeling/Measurement):**
 - **Come up with a way to:**
 - Diagnose where power is going in your system
 - Quantify potential savings
- **Second Component (Design)**
 - Try out lots of ideas
- **This class will focus on both of these at many levels of the computing hierarchy**

How CMOS Transistors Work

NMOS

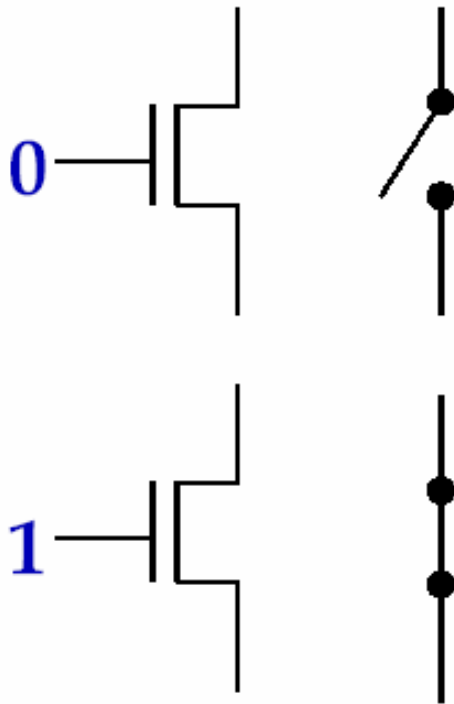


PMOS

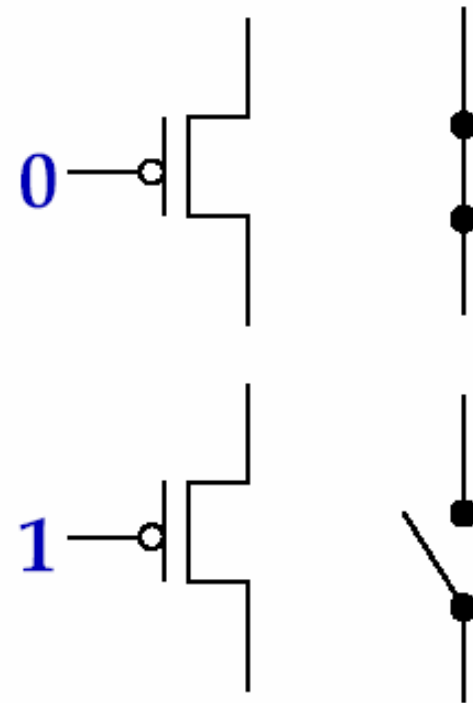


MOS Transistors are Switches

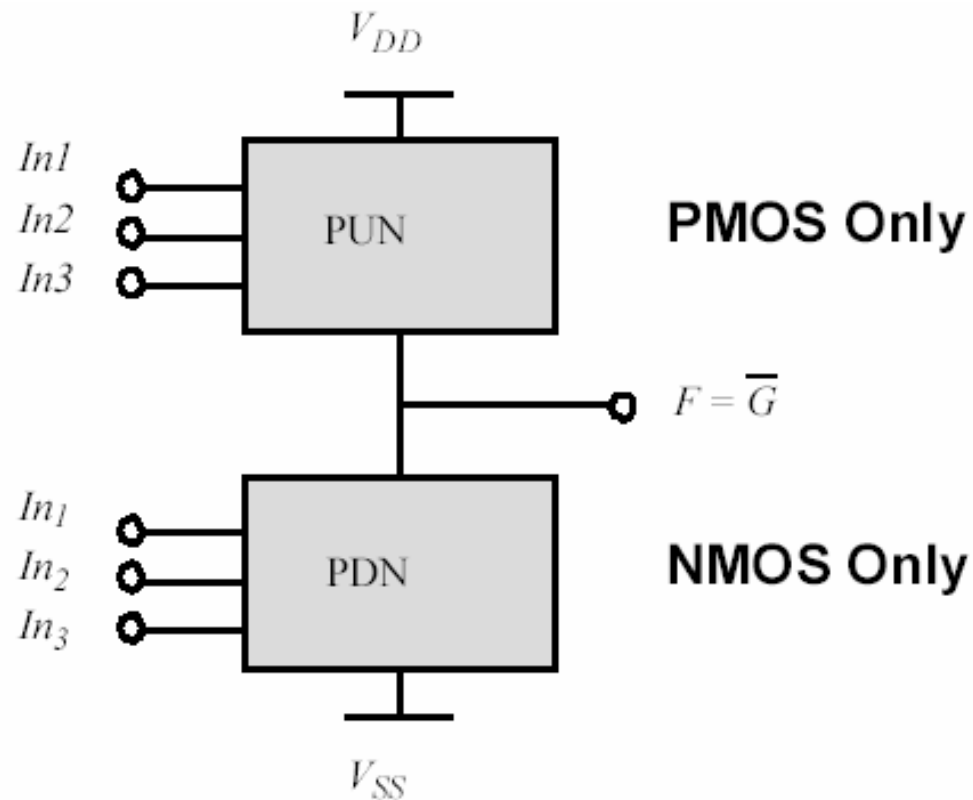
NMOS



PMOS

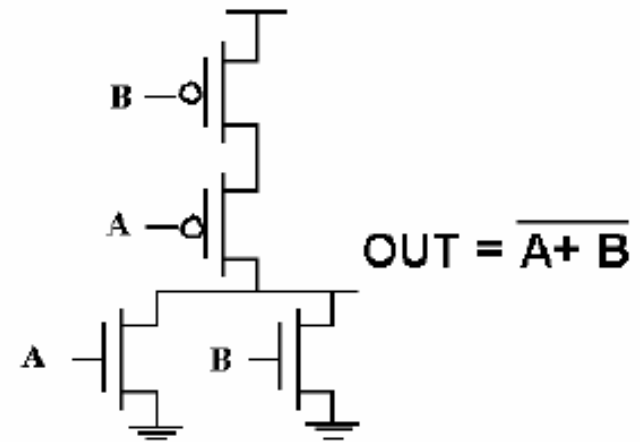
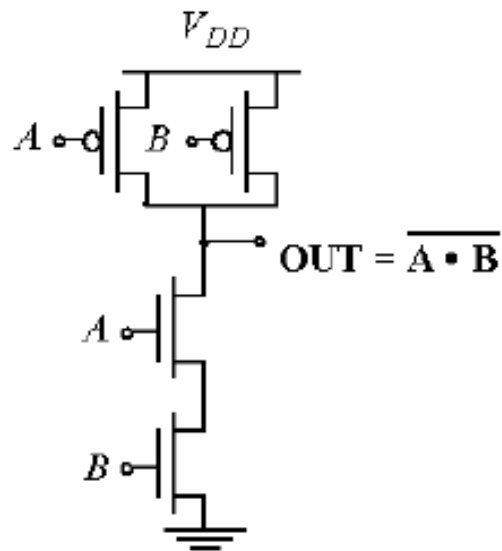
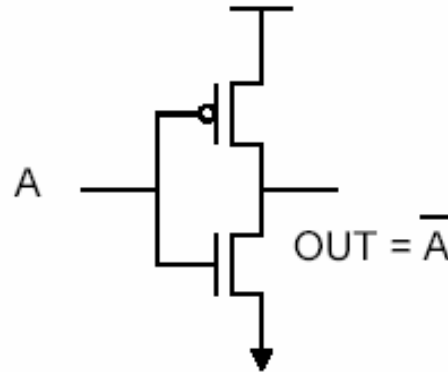


Static CMOS



PUN and PDN are Dual Networks

Basic Logic Gates



CMOS Water Analogy

Electron: water molecule

Charge: weight of water

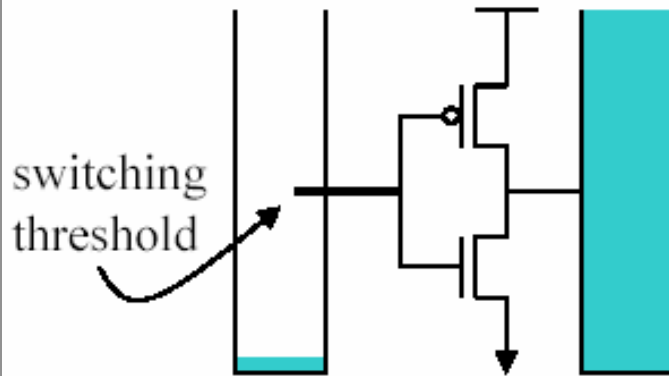
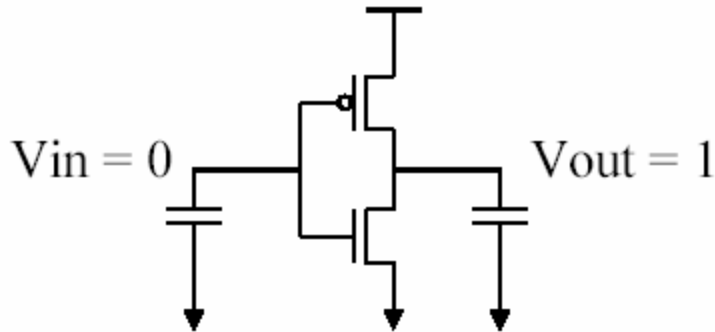
Voltage: height

Current: flow rate

Capacitance: container cross-section

(Think of power-plants that store energy by pumping water into towers)

Liquid Inverter



- **Capacitance at input**
 - Gates of NMOS, PMOS
 - Metal interconnect
- **Capacitance at output**
 - Fanout (# connections) to other gates
 - “Diffusion” capacitance of tx
 - Metal Interconnect

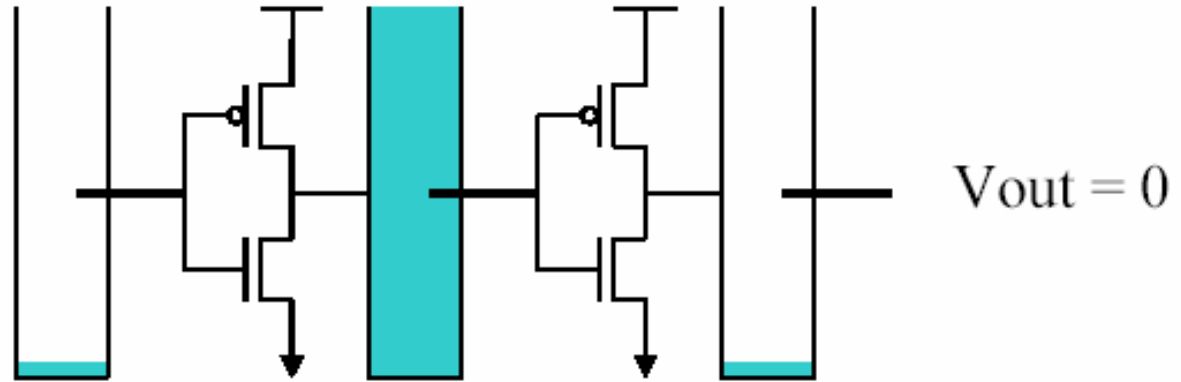
NMOS conducts when water level is above switching threshold

PMOS conducts below

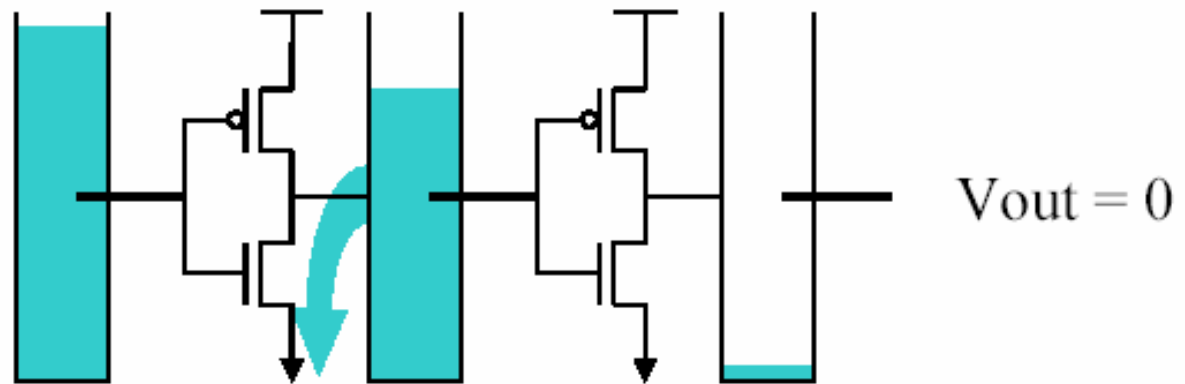
No conduction after container full

Inverter Signal Propagation (1)

$t < 0$
 $V_{in} = 0$

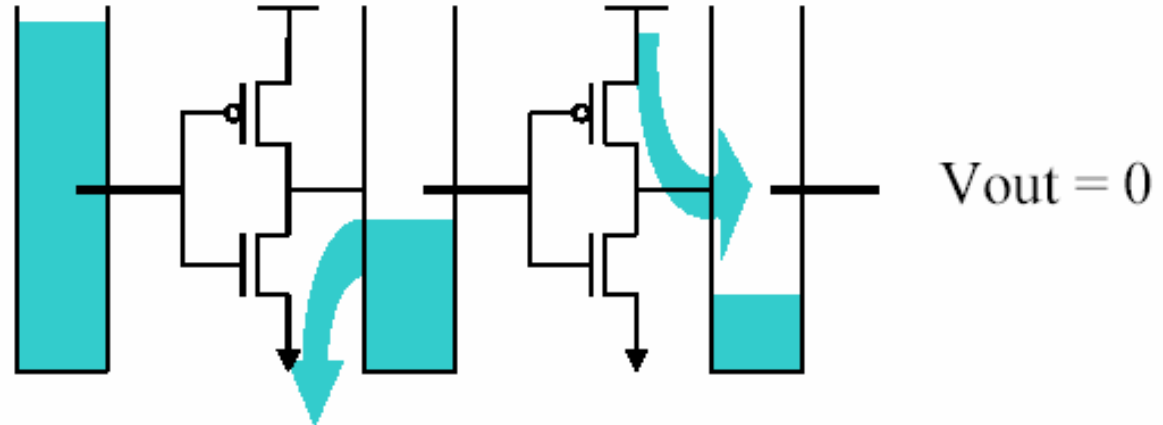


$t = 0$
 $V_{in} = 1$

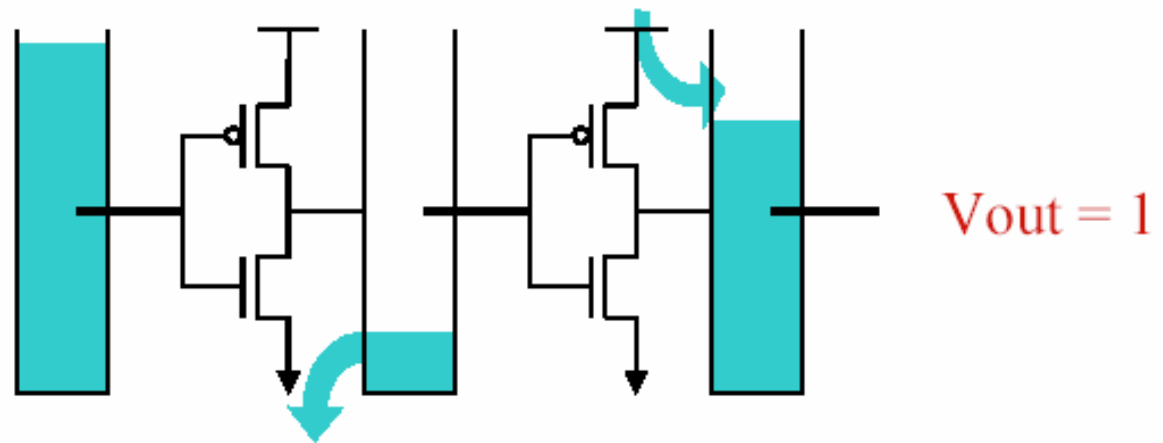


Inverter Signal Propagation (2)

$t = 1$
 $V_{in} = 0$



$t = 2$
 $V_{in} = 1$



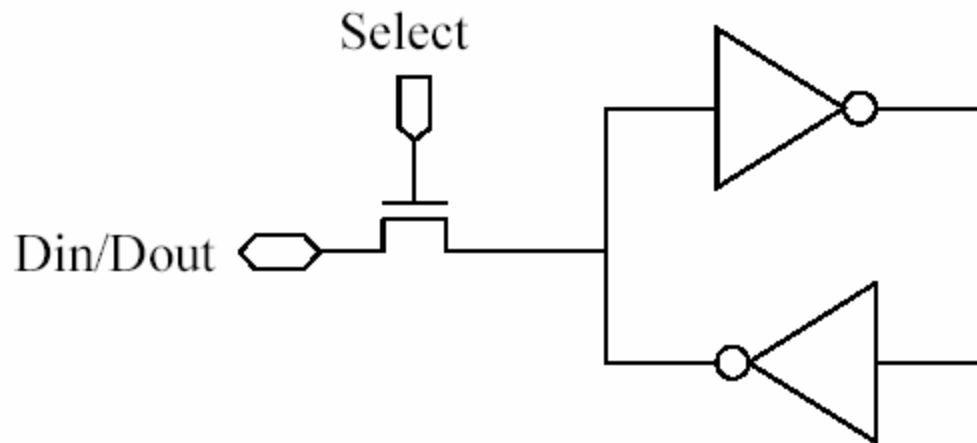
Delay and Energy Definitions

- **Propagation Delay**
 - Time to fill output container to 50%
 - Time to charge output capacitor to 50%
- **Switching Energy**
 - Weight * height of water moved
 - Charge * voltage of charge transferred

Delay and Power Observations

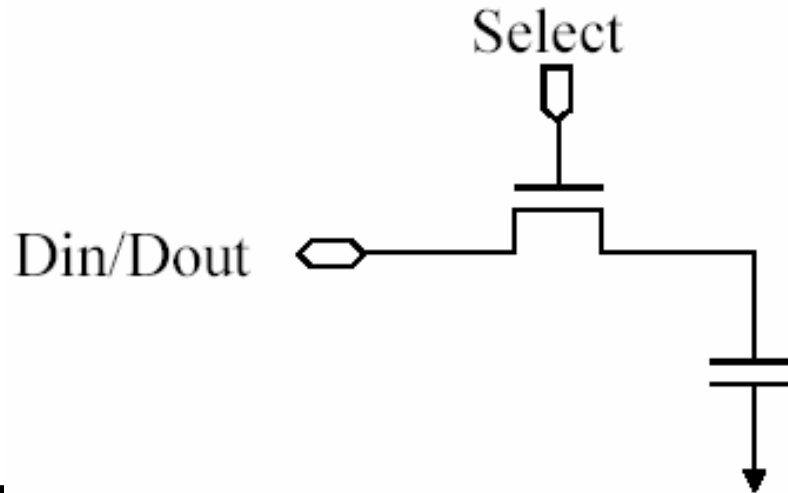
- **Load capacitance increases delay**
 - High fanout (gates attached to output)
 - Interconnection
- **Higher current can increase speed**
 - Increasing transistor width raises currents but also raises capacitance
- **Energy per switching event independent of current**
 - Depends on amount of charge moved, not rate

Feedback-based Latch



- **Pros:**
 - Holds data as long as power applied
 - Actively drives output: (can be fast)
- **Con: Fairly big (5 transistors)**
- **Can be used for latches or SRAM cells**

Charge-based Latch

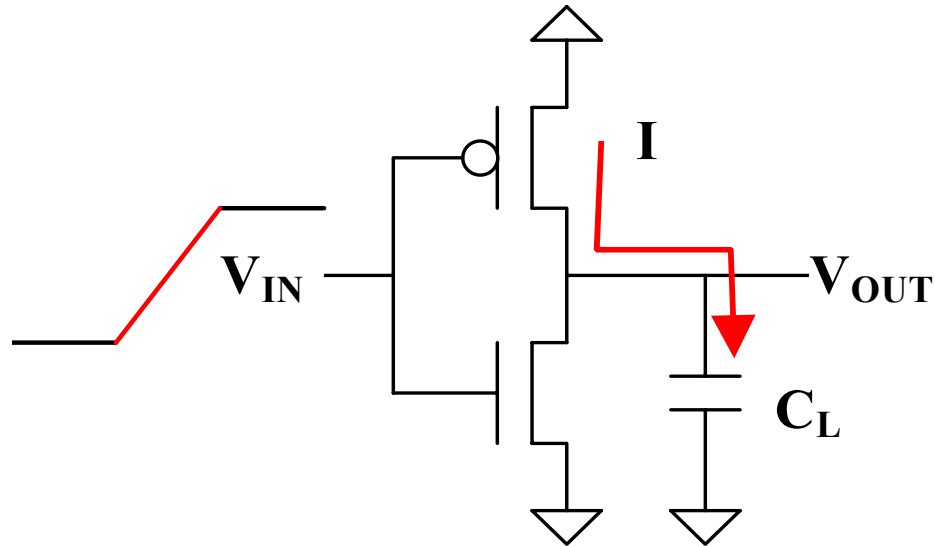


- **Pros:**
 - **Small: 1 transistor, 1 capacitor (may be gate of tx)**
- **Con:**
 - **Charge “leaks” off capacitor (~1ms)**
 - **Reads can be destructive (must read follow by write)**
- **Can be used for latches or DRAM cells**

Power: The Basics

- **Dynamic power vs. Static power**
 - **Dynamic: “switching” power**
 - **Static: “leakage” power**
 - **Dynamic power dominates, but static power increasing in importance**
 - **Trends in each**
- **Static power: steady, per-cycle energy cost**
- **Dynamic power: capacitive and short-circuit**
- **Capacitive power: charging/discharging at transitions from $0 \rightarrow 1$ and $1 \rightarrow 0$**
- **Short-circuit power: power due to brief short-circuit current during transitions.**
- **Most research focuses on capacitive, but recent work on others**

Dynamic (Capacitive) Power Dissipation



- **Data dependent – a function of **switching** activity**

Capacitive Power dissipation

Capacitance:
Function of wire
length, transistor size

Supply Voltage:
Has been dropping
with successive fab
generations

$$\text{Power} \sim \frac{1}{2} CV^2Af$$

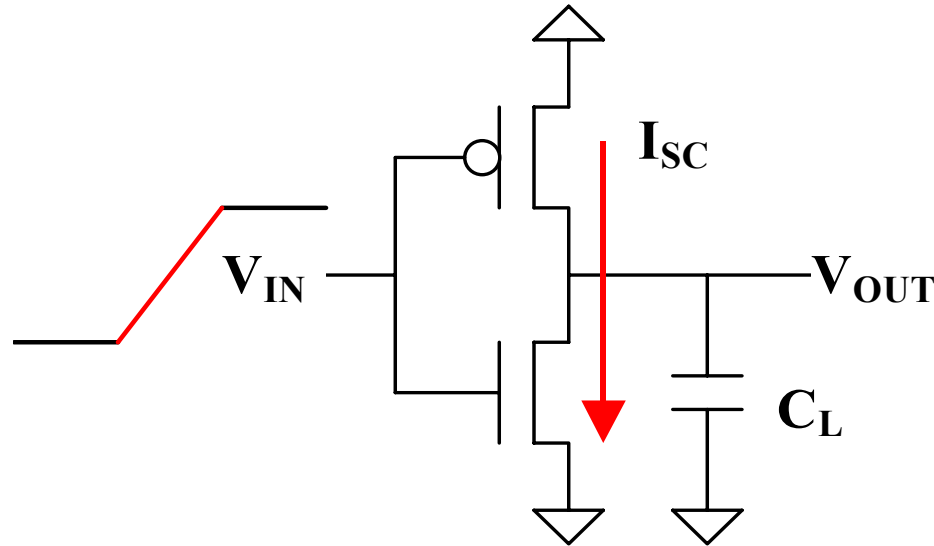
Activity factor:
How often, on average,
do wires switch?

Clock frequency:
Increasing...

Lowering Dynamic Power

- **Reducing V_{dd} has a quadratic effect**
 - Has a negative (~linear) effect on performance however
- **Lowering C_L**
 - May improve performance as well
 - Keep transistors small (keeps intrinsic capacitance (gate and diffusion) small)
- **Reduce switching activity**
 - A function of signal transition stats and clock rate
 - Clock Gating idle units
 - Impacted by logic and architecture decisions

Short-Circuit Power Dissipation



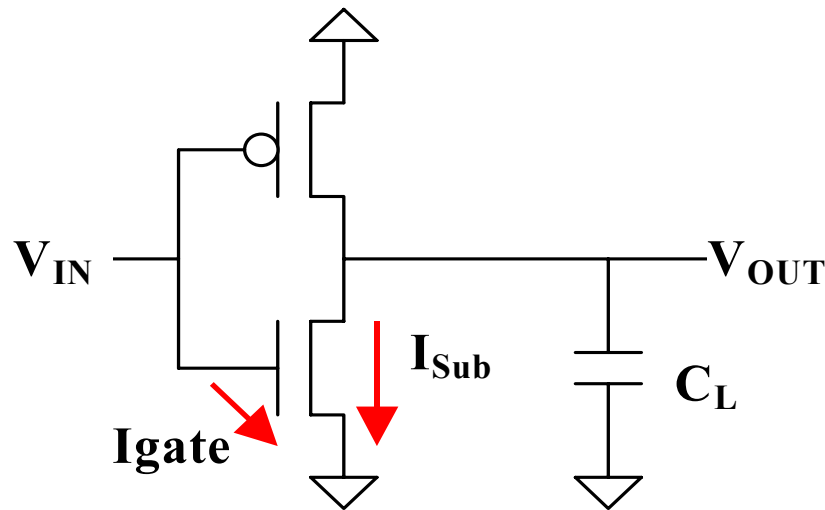
- **Short-Circuit Current caused by finite-slope input signals**
- **Direct Current Path between VDD and GND when both NMOS and PMOS transistors are conducting**

Short-Circuit Power Dissipation

$$\text{Power}_{\text{SC}} \sim t_{\text{sc}} V I_{\text{peak}}$$

- **Power determined by**
 - Duration and slope of input signal, t_{sc}
 - I_{peak} determined by transistor sizes, process technology, C_L
- **Short circuit power can be minimized**
 - Try to match rise/fall times of input and output signals
 - Have not seen many architectural solutions here
 - Good news: relatively, Power_{SC} is shrinking

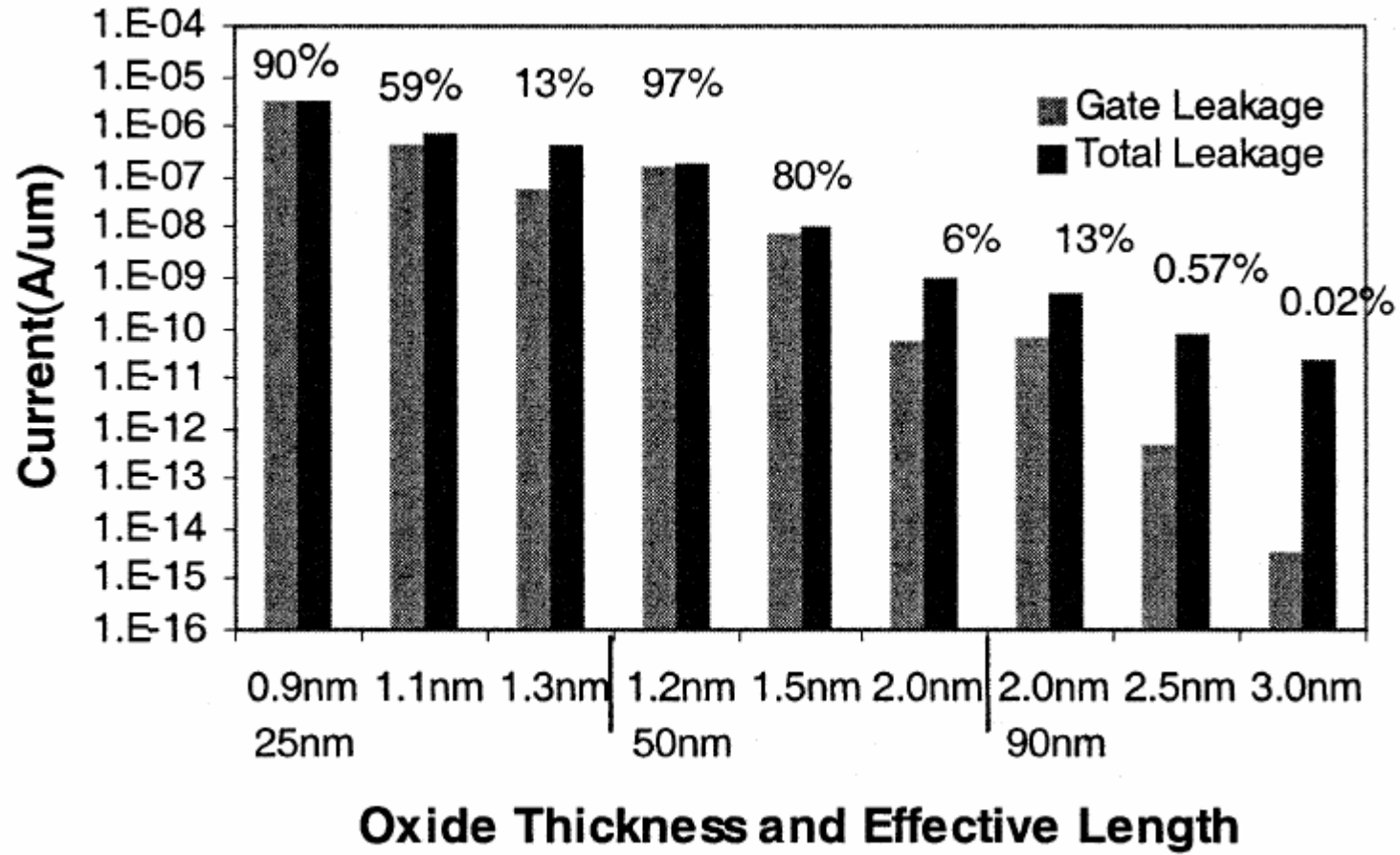
Leakage Currents



$$I_{DSub} = k \cdot e^{\frac{-q \cdot V_T}{a \cdot k_a \cdot T}}$$

- **Subthreshold currents grow exponentially with increases in temperature, decreases in threshold voltage**
 - **But threshold voltage scaling is key to circuit performance!**
- **Gate leakage primarily dependent on gate oxide thickness, biases**
- **Both type of leakage heavily dependent on stacking and input pattern**
- **More on leakage later in the semester**

Gate vs. Subthreshold Leakage

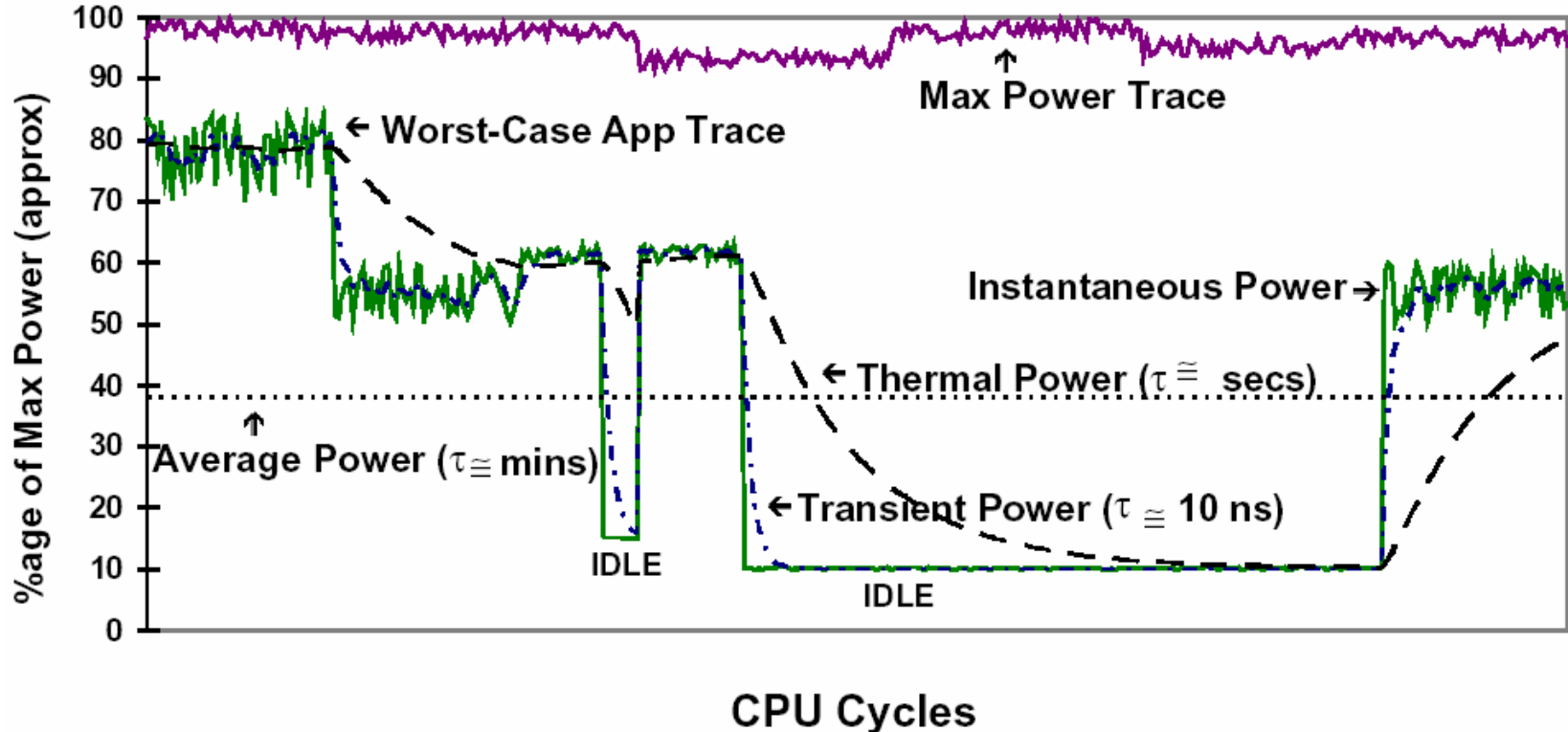


From Mukhopadhyay, et al. TVLSI '03

Lowering Static Power

- **Design-time Decisions**
 - Use fewer, smaller transistors -- stack when possible to minimize contacts with Vdd/Gnd
 - Multithreshold process technology (multiple oxides too!)
 - Use “high-Vt” slow transistors whenever possible
- **Dynamic Techniques**
 - Reverse-Body Bias (dynamically adjust threshold)
 - Low-leakage sleep mode (maintain state), e.g. XScale
 - Vdd-gating (Cut voltage/gnd connection to circuits)
 - Near zero-leakage sleep mode
 - Lose state, overheads to enable/disable

What do we mean by Power?

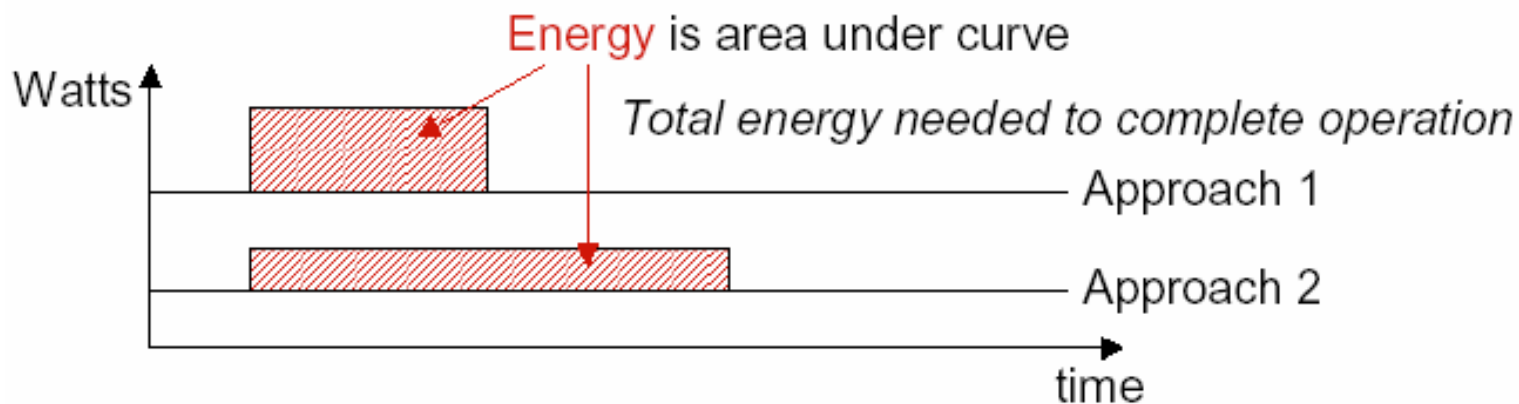
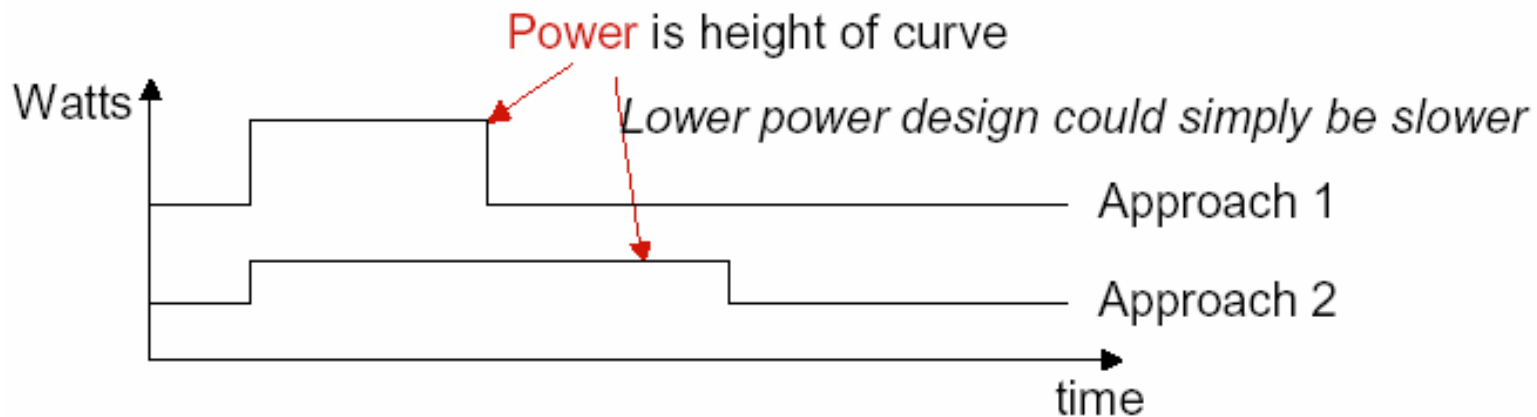


- **Max Power:** Artificial code generating max CPU activity
- **Worst-case App Trace:** *Practical* applications worst-case
- **Thermal Power:** Running average of worst-case app power over a time period corresponding to thermal time constant
- **Average Power:** Long-term average of typical apps (minutes)
- **Transient Power:** Variability in power consumption for supply net

Power vs. Energy

- **Power consumption in Watts**
 - Determines battery life in hours
 - Sets packaging limits
- **Energy efficiency in joules**
 - Rate at which energy is consumed over time
 - Energy = power * delay (joules = watts * seconds)
 - Lower energy number means less power to perform a computation at same frequency

Power vs. Energy



Power vs. Energy

- **Power-delay Product (PDP) = $P_{avg} * t$**
 - PDP is the average energy consumed per switching event
- **Energy-delay Product (EDP) = PDP * t**
 - Takes into account that one can trade increased delay for lower energy/operation
- **Energy-delay² Product (EDDP) = EDP * t**
 - Why do we need so many formulas?!?!?
 - We want a voltage-invariant efficiency metric! Why?
 - Power $\sim \frac{1}{2} CV^2Af$, Performance $\sim f$ (and V)

E vs. EDP vs. ED²P

- **Power $\sim CV^2f \sim V^3$ (fixed microarch/design)**
- **Performance $\sim f \sim V$ (fixed microarch/design)**
- **(For the nominal voltage range, f varies approx. linearly with V)**
- **Comparing processors that can only use freq/voltage scaling as the primary method of power control:**
 - **$(\text{perf})^3 / \text{power}$, or MIPS^3 / W or SPEC^3 / W is a fair metric to compare energy efficiencies.**
 - **This is an ED² P metric. We could also use: $(\text{CPI})^3 * \text{W}$ for a given application**

E vs. EDP vs. ED²P

- **Currently have a processor design:**
 - **80W, 1 BIPS, 1.5V, 1GHz**
 - **Want to reduce power, willing to lose some performance**
 - **Cache Optimization:**
 - **IPC decreases by 10%, reduces power by 20% => Final Processor: 900 MIPS, 64W**
 - **Relative E = MIPS/W (higher is better) = 14/12.5 = 1.125x**
 - **Energy is better, but is this a “better” processor?**

Not necessarily

- **80W, 1 BIPS, 1.5V, 1GHz**
 - **Cache Optimization:**
 - IPC decreases by 10%, reduces power by 20% => Final Processor: 900 MIPS, 64W
 - Relative E = MIPS/W (higher is better) = $14/12.5 = 1.125x$
 - Relative EDP = $\text{MIPS}^2/\text{W} = 1.01x$
 - Relative ED²P = $\text{MIPS}^3/\text{W} = .911x$
- **What if we just adjust frequency/voltage on processor?**
 - How to reduce power by 20%?
 - $P = CV^2F = CV^3 \Rightarrow$ Drop voltage by 7% (and also Freq) => $.93 \cdot .93 \cdot .93 = .8x$
 - So for equal power (64W)
 - Cache Optimization = 900MIPS
 - Simple Voltage/Frequency Scaling = 930MIPS

Analysis Abstraction Levels

<i>Abstraction Level</i>	<i>Analysis Capacity</i>	<i>Analysis Accuracy</i>	<i>Analysis Speed</i>	<i>Analysis Resources</i>	<i>Energy Savings</i>
Application	Most	Worst	Fastest	Least	Most
Behavioral	↑	↓	↑	↓	↑
Architectural (RTL)	↑	↓	↑	↓	↑
Logic (Gate)	↑	↓	↑	↓	↑
Transistor (Circuit)	Least	Best	Slowest	Most	Least

Power/Performance abstractions

- **Low-level:**
 - Hspice
 - PowerMill
- **Medium-Level:**
 - RTL Models
- **Architecture-level:**
 - PennState SimplePower
 - Intel Tempest
 - Princeton Wattch
 - IBM PowerTimer
 - Umich/Colorado PowerAnalyzer

Low-level models: Hspice

- **Extracted netlists from circuit/layout descriptions**
 - **Diffusion, gate, and wiring capacitance is modeled**
- **Analog simulation performed**
 - **Detailed device models used**
 - **Large systems of equations are solved**
 - **Can estimate dynamic and leakage power dissipation within a few percent**
 - **Slow, only practical for 10-100K transistors**
- **PowerMill (Synopsys) is similar but about 10x faster**

Medium-level models: RTL

- **Logic simulation obtains switching events for every signal**
- **Structural VHDL or verilog with zero or unit-delay timing models**
- **Capacitance estimates performed**
 - **Device Capacitance**
 - **Gate sizing estimates performed, similar to synthesis**
 - **Wiring Capacitance**
 - **Wire load estimates performed, similar to placement and routing**
- **Switching event and capacitance estimates provide dynamic power estimates**

Architecture level models

- **Two major classes:**
 - **Cycle/Event-Based:** Arch. Level power models interfaced with cycle-driven performance simulation
 - **Instruction-Based:** Measurement/Characterization based on instruction usage and interactions
 - **Components of Arch. Level power model**
 - **Could be based on ckt schematic measurements/extrapolation**
- Or...
- **Capacitance models**
- Both may need to consider...
- **Circuit design styles**
 - **Clock gating styles & Unit usage statistics**
 - **Signal transition statistics**

Paper Readings

- **Background Material (available on website)**
 - **Power-Aware Microarchitecture: Design and Modeling Challenges for Next-Generation Microprocessors,” IEEE MICRO.**
 - **“Power: A First-Class Architectural Design Constraint,” IEEE Computer.**